Туре	ı	# Hi	Lts	Search Text	DBs	Time Stamp	Commen	Error Definition	E L
 IS&R		7		PN.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_	2006/07/ 05 16:14			
IS&R	1.2	5	- 	(("6636998") or ("6856158") or ("6978405") or ("6182255") or ("6094735")).PN.	USPA T	2006/07/ 05 16:15			
BRS	T 2	18	51	702/117.ccls. or 327/40.ccls. or 714/719.ccls.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_	2006/07/ 05 16:34			

	Type	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	E ro rs
	BRS	T 6	1160	or or) and	US- PGPU B; USPA T; JPO; DERW ENT; IBM_	2006/07/ 05 16:19			
10	BRS	1.7	230	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information).	USPA USPA I; UPO; UPO; UPO; TERW	2006/07/ 05 16:35			

	Type	н	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
9	BRS	T.8		112	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:35			
7	BRS	0 1		5.3	l L	US- PGPU B; USPA T; TPO; JPO; DERW ENT; TBM_	2006/07/ 05 16:35			

	Type L	# 1	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
ω	BRS	L10	o o	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and juda\$5	US- PGPU B; USPA T; JPO; JPO; TERW TBM	2006/07/ 05 16:38			

Type	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	E ro rs
BRS	L11	Н	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and Polocks1 with test\$3 B, with (device\$1 or unit\$1) same (compar\$4 or differen\$2) with (data or Elinformation) with output\$4 and judg\$5 The process\$3	S- SPU ; SPA ; PO; PO; NT; SM	2006/07/ 05 16:38			

Type	# H	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
O BRS	L12	m	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and PGPU block\$1 with test\$3 B; with (device\$1 or USPE circuit\$1 or USPE circuit\$1 and (compar\$4 or differen\$2) with (bit\$1 with (data or ENT) information) with output\$4 and judg\$5 TDB and logical\$2 with process\$3	S- 3PU ; SPA ; PO; PO; BM_ DB_	2006/07/ 05 16:29			

	Type	# #	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro
∺	BRS	L13	~	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and block\$1 with test\$3 with (device\$1 or circuit\$1 or differen\$2 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; JPO; JPO; TPO; TBM_ TDB_	2006/07/			

Type	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
2 BRS	L14	4	block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with B; bit\$1 with (data or USPA information) with T; reference\$1 or EPO; predetermined or JPO; preset\$4 or preset\$4 or preset\$4 or preset\$5 and or threshold\$1) and TDB judg\$5 and logical\$2 with process\$3		2006/07/ 05 16:31			

						Time	Commen	Error	E T
	Type	# 니 	Hits	Search Text	DBs	Stamp	t s	Definition	ro
				(array\$1 or block\$1					
				or serial) with					
				test\$3 with					
				(device\$1 or					
					us-				
				unit\$1) and	PGPU				
				ompar\$4 or	B;				
				differen\$2) with	USPA				
				bit\$1 with (data or T;	Τ;	/ 20/ 9000			
m	BRS	L15	9	information) with	EPO;	2000/01/ 05 16.31			
				(reference\$1 or	JPO;	· · · · · · · · · · · · · · · · · · ·			
				predetermined or	DERW				
				eset\$4 or	ENT;				
				edefined or	IBM				
				expected or desired TDB	TDB				
				or threshold\$1) and					
				judg\$5 and					
				logical\$2 with					
				process\$3			:		

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4	BRS	L16	2166	or or	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_	2006/07/ 05 16:37			
က်	BRS	L17	230	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information)	US- PGPU B; USPA T; JPO; DERW ENT; IBM	2006/07/ 05 16:37			

	Туре	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	E L C S L C
v	BRS	L18	112	or r and th ta or	US- PGPU B; USPA T; JPO; JERW ENT; IBM_	2006/07/ 05 16:37			
.7	BRS	L19	53	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; JPO; JPO; TPB TDB	2006/07/ 05 16:37			

	Туре	# 	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
æ	BRS	L20	6772	or r or ls.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_	2006/07/ 05 16:37			
<u></u> 6	BR.S.	1.21	5 8 6	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information)	US- PGPU B; USPA T; JPO; DERW ENT; IBM	2006/07/ 05 16:37			

	Type	다 #	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
20	BRS	L22	134	or r or and th ta or ith	US- PGPU B; USPA T; UPO; UPO; TEM TDB	2006/07/ 05 16:37			
21	BRS	L23	09	or r and and th ta or	US- PGPU B; USPA T; JPO; DERW ENT; IBM_	2006/07/ 05 16:38			

	Туре	ı	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
22	BRS	L24		0	(702/117.ccls. or 327/40.ccls. or US-714/719.ccls. or PGPU 324/765.ccls.) and B; test\$3 with USPZ (device\$1 or Circuit\$1 or EPO, unit\$1) same DERV differen\$2) with ENT ENT information) with TDB information) with TDB	h d	2006/07/ 05 16:38			
					output 4 and Judg 5					

	Туре	# 1	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	E ro rs
23	BRS	L25	7	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or US-324/765.ccls.) and PGPU block\$1 with test\$3B; with (device\$1 or USPA circuit\$1 or USPA circuit\$1 or USPA circuit\$1 or USPA differen\$2) with DERW bit\$1 with (data or ENT; information) with IBM output\$4 and judg\$5 TDB and logical\$2 with process\$3		2006/07/ 05 16:38			
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						င်းမျာ	3	חבר דווד כדסוו	rs
				(702/117.ccls. or					
				327/40.ccls. or					
				714/719.ccls. or					
				324/765.ccls.) and					
				test\$3 with					
				(device\$1 or	us-	/ 20/ 9000			
4	BRS	L26	<u>o</u>		PGPU	Z000/01/			
				unit\$1) same	В				
				(compar\$4 or					
				differen\$2) with					
				bit\$1 with (data or					
				information) with					
				output\$4					

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	Type	# 	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	다 O 다 다 S 다
				(702/117.ccls. or					
				32//40.ccls. or					
				714/719.ccls. or					
				324/765.ccls.) and					,
				(array\$1 or block\$1					
				or serial) with					
				test\$3 with					
				(device\$1 or					
				circuit\$1 or	0				
Ц	000	T 0.7	,	unit\$1) and	ומטמ	2006/07/			
?	240	, 7 <u>1</u>	7			05 16:39			
				with	Ω				
				bit\$1 with (data or					
				information) with	-				
				(reference\$1 or					
				predetermined or					
				preset\$4 or					
				predefined or					
				expected or desired					
				or threshold\$1)					

	Туре	#	Hits	Search Text	DBs	Time Stamp	Commen	Error Definition	Er ro rs
9	BRS	L28	J	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and compar\$4 or PGPU differen\$2) with B; bit\$1 with (data or USPA information) with T; creference\$1 or EPO; predetermined or DERW predefined or desiredIBM expected or desiredIBM		2006/07/			
				or threshold\$1) and TDB judg\$5 and logical\$2 with process\$3 and nonvolatile with memory	TDB_				

	Type	H	#	Hits	Search Text	DBs	Time	Commen	Error	Erro
	1						Stamp	ts	Definition	rs
					(array\$1 or block\$1					
					or serial) with					
					test\$3 with					
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						T D M				
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					or threshold $\$1$) and 1DB					
					logical\$2 with					
					process\$3 and non-			_		
					volatile with					
	į				memory					

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ω.	BRS	T 30	F-1	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with uspabit\$1 with (data or T; information) with EPO; predetermined or DERW preset\$4 or predefined or desired TDB or threshold\$1) and logical\$2 with process\$3 and non-volatile with memory and judge\$5		2006/07/			·

	Þ	1 Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
н		US 2006006426 5 A1	20060323	16	System and method for burn-in test control	702/117		702/117
N	×	US 2006004746 20060302 3 A1	20060302	17	Bit synchronization for high-speed serial device testing	702/120	702/117	702/117
м	×	us 2005011406 20050526 3 A1	20050526	34	Semiconductor device and testing circuit which can carries out a verifying test effectively for non- volatile memory cells	702/117		702/117
7	×	US 2004004658 6 A1	20040311		Semiconductor integrated circuit	324/765		324/765
Ŋ	×	US 2003021731 3 A1	20031120		Method and auxiliary device for testing a 714/719 RAM memory circuit	714/719		714/719

	Þ	н	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva l Classif
12	×		US 2001004223 2001111 1 A1	20011115		Memory testing apparatus and method	714/719		714/719